

# Electronic Information Disclosure Statement

## Ionic Pre-concentration XRF Detection and Analysis Device, System and Method

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jc474 U.S. PTO  
10/065683  
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Application:

Confirmation:

Applicant(s): Robert Keville

Docket

ISIP017US

Number:

Group Art Unit:








Examiner:






Unknown

search string: ( 5192432 or 5200068 or 5360540 or 5415768 or 5425858 or 5538611 or 5547581 or 5620597 or 5779891 or 5834633 or 5945084 or 5954937 ).pn.

### US Patent Documents

**Note: Applicant is not required to submit a paper copy of cited US Patent Documents**

init	Citation No.	Patent Number	Date	Bar Code	Patentee	Class	Subclass
	P01	5192432	1993-03-09		Andelman	204	665
	P02	5200068	1993-04-06		Andelman	204	645
	P03	5360540	1994-11-01		Andelman	210	198.2
	P04	5415768	1995-05-16		Andelman	210	198.2
	P05	5425858	1995-06-20		Farmer	204	450
	P06	5538611	1996-07-23		Otowa	204	550
	P07	5547581	1996-08-20		Andelman	210	656

	P08	5620597	1997-04-15		Andelman	210	198.2
	P09	5779891	1998-07-14		Andelman	210	198.2
	P10	5834633	1998-11-10		Davison	73	53.01
	P11	5945084	1999-08-31		Droege	423	447.4
	P12	5954937	1999-09-21		Farmer	205	687

## Remarks

(Remarks are not for responding to an office action.)

All of the references cited in this information disclosure have already been discussed at length in the specification as filed. This discussion in the filed specification will be relied upon to provide a "concise explanation of relevance," which, of course, is nevertheless optional for English-language references. (See 37 CFR 1.98(a)(3) and MPEP 609 A(2) and A(3)).

## Signature

Examiner Name	Date